M. Brunson 6/21/01 PATENT



Docket No.: 4653/PDC/WF/LE

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Daniel I SOME, et al.

Serial No.: unassigned

Group Art Unit: unassigned

Filed: unassigned

Examiner: unassigned

For:

LASER SCANNING WAFER INSPECTION USING NONLINEAR OPTICAL

PHENOMENA

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents Washington, DC 20231

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

Respectfully submitted

Rôbert W. Mulcahy Registration No. 25,436

Patent Counsel APPLIED MATERIALS, INC. Legal Affairs Department P.O. Box 450A Santa Clara, CA 95052 **Date:**